

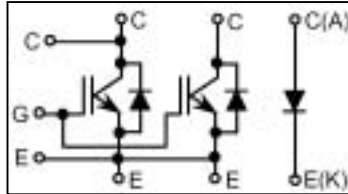
MBL800D33C

Silicon N-channel IGBT

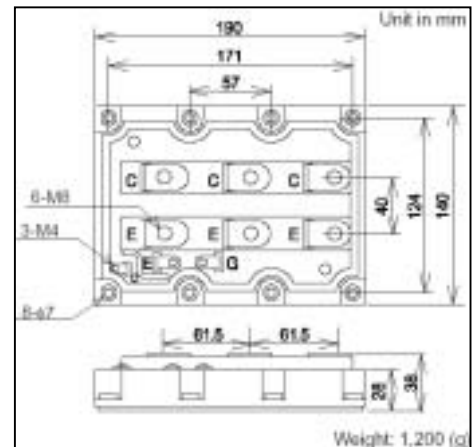
FEATURES

- * High thermal fatigue durability. ($\Delta T_c=70^\circ\text{C}$, $N>30,000$ cycles)
- * low noise due to built-in free-wheeling diode – ultra soft fast recovery diode(USFD).
- * High speed, low loss IGBT module.
- * Low driving power due to low input capacitance MOS gate.
- * High reliability, high durability module.
- * Isolated head sink (terminal to base).

CIRCUIT DIAGRAM



OUTLINE DRAWING



ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$)

Item	Symbol	Unit	MBL800D33C
Collector Emitter Voltage	V_{CES}	V	3,300
Gate Emitter Voltage	V_{GES}	V	± 20
Collector Current	DC	I_C	800
	1ms	I_{Cp}	1,600
Forward Current	DC	I_F	800
	1ms	I_{FM}	1,600
Collector Power Dissipation	P_C	W	8,000
Junction Temperature	T_j	$^\circ\text{C}$	-40 ~ +125
Storage Temperature	T_{stg}	$^\circ\text{C}$	-40 ~ +125
Isolation Voltage	V_{ISO}	V_{RMS}	6,000 (AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/10 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value $1.8 \pm 0.2/9 \pm 1 \text{N}\cdot\text{m}$ (2) Recommended Value $5.5 \pm 0.5 \text{N}\cdot\text{m}$

CHARACTERISTICS ($T_c=25^\circ\text{C}$)

1) IGBT + FWD

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions							
Collector Emitter Cut-Off Current	I_{CES}	mA	-	-	12.0	$V_{CE}=3,300\text{V}$, $V_{GE}=0\text{V}$							
Gate Emitter Leakage Current	I_{GES}	nA	-	-	± 500	$V_{GE}=\pm 20\text{V}$, $V_{CE}=0\text{V}$							
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	-	4.1	5.0	$I_C=800\text{A}$, $V_{GE}=15\text{V}$							
Gate Emitter Threshold Voltage	$V_{GE(To)}$	V	4.5	5.5	6.5	$V_{CE}=5\text{V}$, $I_C=800\text{mA}$							
Input Capacitance	C_{ies}	nF	-	100	-	$V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{KHz}$							
							Rise Time	t_r	μs	-	2.0	3.2	$V_{CC}=1,650\text{V}$, $I_C=800\text{A}$
							Turn On Time	t_{on}	μs	-	2.9	3.8	$L=120\text{nH}$
							Fall Time	t_f	μs	-	1.7	3.2	$R_G=4.7\Omega$ (3)
Peak Forward Voltage Drop	V_{FM}	V	-	2.2	2.8	$-I_C=800\text{A}$, $V_{GE}=0\text{V}$							
Reverse Recovery Time	t_{rr}	μs	-	0.8	1.4	$V_{CC}=1,650\text{V}$, $I_F=800\text{A}$ (4) $L=120\text{nH}$, $T_c=125^\circ\text{C}$							
Thermal Impedance	IGBT	$R_{th(j-c)}$	$^\circ\text{C/W}$	-	-	0.012	Junction to case						
	FWD	$R_{th(j-c)}$	$^\circ\text{C/W}$	-	-	0.024							

2) DIODE

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	I_{AKS}	mA	-	-	12.0	$V_{AK}=3,300\text{V}$
Peak Forward Voltage Drop	V_F	V	-	2.4	3.0	$I_F=800\text{A}$
Reverse Recovery Time	t_{rr}	μs	-	0.8	1.4	$I_F=800\text{A}$, $V_{CC}=1,650\text{V}$ (4) $L=120\text{nH}$, $T_c=125^\circ\text{C}$
Thermal Impedance	$R_{th(j-c)}$	$^\circ\text{C/W}$				0.024 Junction to case

Notes: (3) R_G value is the test condition's value for decision of the switching times, not recommended value. Determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

(4) Counter arm IGBT $V_{GE}=-15\text{V}$

HITACHI POWER SEMICONDUCTORS

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